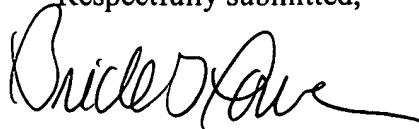


REMARKS

This amendment corrects errors in the text and drawings. Entry is respectfully solicited.

This amendment is submitted prior to or concurrently with the payment of the issue fee and, therefore, no petition or fee is required. No new matter has been added.

Respectfully submitted,



Brick G. Power
Registration No. 38,581
Attorney for Applicants
TRASKBRITT, PC
P.O. Box 2550
Salt Lake City, Utah 84110-2550
Telephone: 801-532-1922

Date: December 22, 2004

BGP/df/rh

\Traskbritt1\Shared\DOCS\2269-5467.1US\93151.doc

IN THE DRAWINGS:

The attached drawing includes a change to FIG. 3. This sheet replaces the original sheet including FIG. 3.

Specifically, FIG. 3 has been revised to change the reference numeral "51" to --52--. No new matter has been added.

TITLE: WAFER-LEVEL TESTING
APPARATUS AND METHOD

Inventor: Farnsworth et al.

Serial No.: 10/669,949

Docket No.: 2269-5467.1US

ANNOTATED SHEET

3/7

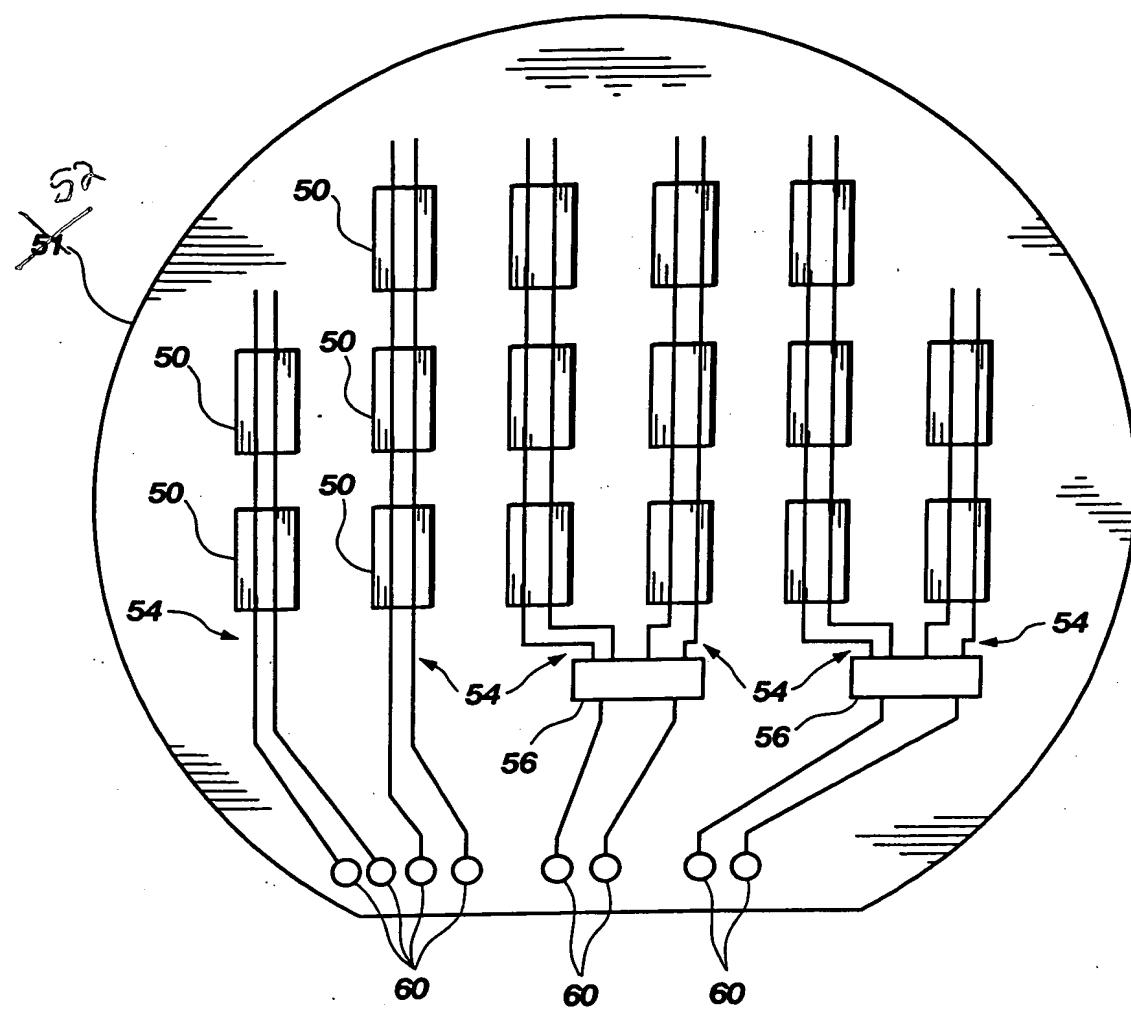


FIG. 3

+